

# 10 CPU 857-6813

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### 10.3 INTERFACE CONNECTIONS

1A01	0V	1B01	ASR LINE
1A02	PIFN	1B02	RTC AN
1A03	CPFN	1B03	SCEIN
1A04	IS02N	1B04	IS05N
1A05	PFFN	1B05	IS04N
1A06	BIEC4	1B06	RTCFZ1N
1A07	BIEC2	1B07	BIEC1
1A08	BIEC5	1B08	BIEC3
1A09	IS06N	1B09	BIEC0
1A10	IS03N	1B10	IS07N
1A11	IS01N	1B11	IS00N
1A12	INTASRN (INTSERN)	1B12	
1A13		1B13	
1A14		1B14	
1A15		1B15	
1A16		1B16	
1A17		1B17	
1A18		1B18	
1A19		1B19	
1A20		1B20	
1A21		1B21	
1A22		1B22	
1A23		1B23	
1A24		1B24	
1A25		1B25	
1A26		1B26	
1A27	0V	1B27	0V
1A28	5V	1B28	5V
1A29		1B29	
1A30	Mech. Ground	1B30	
1A31	CT103	1B31	0V
1A32	CT104	1B32	0V
1A33	CT106	1B33	0V
1A34	CT107	1B34	0V
1A35	CT1082	1B35	0V
1A36	CT109	1B36	0V
1A37	CT133	1B37	0V

Table 10.1 CPU B CONNECTOR 1 (V24 CU)

5A01	
5A02	
5A03	
5A04	
5A05	
5A06	
5A07	
5A08	
5A09	
5A10	* SP03
5A11	* FLOACTN
5A12	* BSYCPUAN
5A13	* GFETCH
5A14	* DONEFN
5A15	* FLOCRI
5A16	
5A17	* OSCFLO
5A18	
5A19	* MMUABS
5A20	* DONEMN
5A21	* BOMFN
5A22	* FU
5A23	* S01
5A24	* S03
5A25	* SP02
5A26	
5A27	* 0V
5A28	* 5V
5A29	BIOEKEY
5A30	UNLOCKN
5A31	RUNN
5A32	RCP00N
5A33	LOADRN
5A34	READSTN
5A35	RCP03N
5A36	LOADMN
5A37	READRN

5B01	* SP05
5B02	* GBCPFN
5B03	* PREQN
5B04	* CPBABS
5B05	* TESTN
5B06	
5B07	
5B08	
5B09	
5B10	* SP04
5B11	* SP01
5B12	* TMFN
5B13	* BOFFN
5B14	* PLOCRO
5B15	* FPPABS
5B16	
5B17	OV
5B18	
5B19	
5B20	* MFAULTN
5B21	
5B22	* S00
5B23	* S02
5B24	* TMMN
5B25	* TMMU
5B26	
5B27	* 0V
5B28	* 5V
5B29	CPMCN
5B30	IPL
5B31	START
5B32	CPINT
5B33	RUNFA
5B34	RCP01N
5B35	RCP02N
5B36	READMN
5B37	INSTN

Table 10.2 CPU B CONNECTOR 5

Notes: (device interfaces)

Signal Name	Pin No's (Line Connector P5)		CPU	Conn. P7
Ready for Receiving	25	CT 133	1A37	
Operational Signal	19			
Operational Signal	18			
Data Termin. Ready	20	CT 108-2	1A35	
Data Set Ready	6	CT 107	1A34	
Received Data	3	CT 104	1A32	
Transmitted Data	2	CT 103	1A31	
Protective Ground	1	CT 101		
Signal Ground	7	CT 102	1B31-1B37	

Table 10.3 PER 3100 INTERFACE

## 10.4 HARDWARE SOFTWARE INTERFACE DETAILS

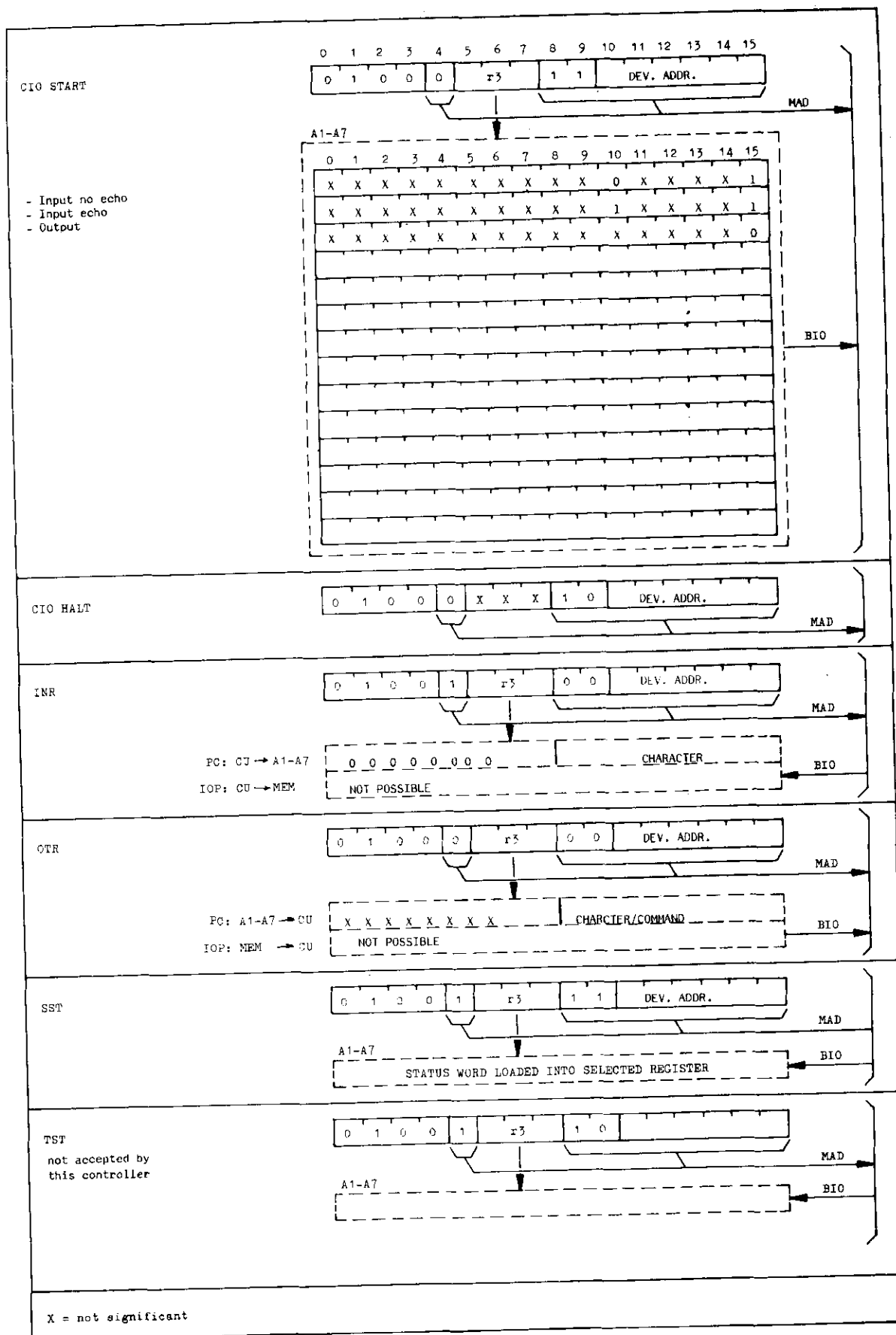


Figure 10.2 INSTRUCTION/COMMAND WORD FORMATS

#### 10.4.1 STATUSWORD:

0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
0	0	0	0	0	0	0	0	0	0	0	0	0			

DATA FAULT

THROUGHPUT ERROR

NOT OPERABLE

##### Not Operable

Bit 15 is set if the device is not connected or not operable.

##### Through put error

Bit 14 is set during input mode, if the interrupt is not yet answered by the CPU (INR) and the next input character arrives.

##### Parity error

Bit 13 is set when during input mode the received character has incorrect parity (not as is strapped).

## 10.5 SHORT DESCRIPTION TESTPROGRAMS

### MICRODIAGNOSTICS

The P856M and the P857M contain an automatic testing feature in the form of a microprogrammed diagnostic built into the CPU logic. Successful running of the tests indicate that sufficient parts of the CPU function for loading of test programs.

The microdiagnostics for the P856M test the first 4k of memory and for the P857M the first 16k of memory. The prerequisite tool is the FULL CONTROL PANEL or the EXTENDED CONTROL PANEL, as the results of the tests are displayed on the data lamps.

About 100 words are reserved for the microdiagnostic program.

The test can only be performed when the jumper NORM/DIGNOS IS in the DIAGNOS position see figure 4.2-1 and an EFP or CFP is fitted (On 6810 UK and earlier models of PTS 6813 force pin 5B05 on backpanel 1C to ground).

### TEST PROCEDURES

Before starting any test, except for steps A to D included in the Test 2, the user has to set a control unit address on data switches 2 to 7 included to check the dialogue through the Bus between the CPU and the control unit.

#### *Test 1 Automatic Test*

This is a fast check which automatically goes through a number of operations. If the tests have been satisfactory special codes are displayed on the data lamps.

- set data switch 0 to 0
- set a control unit address on data switches 2 thru 7
- press RUN button
- wait for display of code no 4
  - code 4: data lamp 12 off
  - all other lamps lit
- if this code is not displayed go to Test 2
- press LM button and wait for display of code 5
  - code 5: all lamps lit
- If the code is not displayed go to Test 2.

#### *Test 2 Step-by-step testing*

This sequence may be used if Test 1 showed an erroneous display or if the user wishes to perform separate tests. In these tests the user verifies the operation of the control panel up to the memory.

##### **A. Control Panel test**

Each data key and the lamp above it are tested by setting the key in the 'up' position after which the lamp must be lit. Press LR button to go to the next step.

##### **B. L register test**

This step includes the GP BUS and the L register in the test. The operator may use the switches in the same way as described under control panel. Press LR button to go to the M register test.

##### **C. M register test**

This step includes the M register (through the C selector and ALU) in the test. The operator may use the switches in the same way as described under control panel. Press the LR button to go to the Q register test.

##### **D. Q register test**

This step includes the Q register in the test. The operator may use the switches in the same way as described under control panel.

From this moment on the operator may choose among three data path tests, an instruction simulation test or a memory test by setting on the data switches a hexadecimal number and a control unit address, followed by pressing the LR button.

If the relevant test is executed without errors the data lamps display a certain code.

It is possible to skip the visual tests A thru D. The user must then set switch 0 to 0, set a control unit address on switches 2 thru 7, and set switch 15 to 1. Next press the LR button 4 times. Then wait for display of code 1. Press LR button and wait for display of code 2. Press LR button and wait for display of code 3. Press LR (or RUN) button for display of code 4. Press LM (or LR) button for display of code 5.

### *Test 3 Chained test*

In this mode the hardware is tested in a loop which may be stopped by operation of data switch 0.

- set data switch 0 to 1, a control unit address on switches 2 thru 7, and switch 15 to 1.
- press LR button 4 times. The microprogram starts looping.

To stop the loop:

- set switch 0 to 0.

One of the 5 codes as listed above is displayed. If it is not code 5 press the LR button as many times until code 5 appears.

To restart the loop set switch 0 to 1.

To restart at the beginning of the test turn the key in the key switch to OFF and next to TEST. Set switch 0 to 1, set the control unit address, and set switch 15 to 1 and continue as described above.



	Hexa no on data switches	Test functions	Display on data lamps when no fault is found
data path test	/0001 + CU address	<ul style="list-style-type: none"> <li>- shift left Q reg.</li> <li>- bus A selection</li> <li>- constant 'TWO'</li> <li>- QO test</li> <li>- A or B, A+B and B inverted</li> <li>- ALU functions</li> <li>- ALU = 0</li> </ul>	code 1 lamp 15 OFF all other lamps lit
data path test	/0002 + CU address	<ul style="list-style-type: none"> <li>- shift right Q reg.</li> <li>- ALUZERO</li> <li>- A-B, A+B and crossed</li> <li>- A ALU functions</li> <li>- constant 'TEN'</li> <li>- P reg. P - 2 function</li> </ul>	code 2 lamp 14 OFF all other lamps lit
data path test	/0004 + CU address	<ul style="list-style-type: none"> <li>- A operand shifted right</li> <li>- 4 x A function</li> <li>- reading and writing scratch pad</li> </ul>	code 3 lamp 13 OFF all other lamps lit
instruction simulation	/0008 + CU address	<p>DLA</p> <ul style="list-style-type: none"> <li>- K is loaded with DLA code</li> <li>- values loaded in A1 and A2</li> <li>- branch to DLA micro program</li> <li>- return to microdiagnostic program</li> </ul> <p>RB</p> <ul style="list-style-type: none"> <li>- K is loaded</li> <li>- RB microprogram next address generated by PLA</li> </ul>	code 4 lamp 12 OFF all other lamps lit
memory test	/0010 + CU address	<ul style="list-style-type: none"> <li>- bit 15 is set to 1 in all addresses of a 4k/16k block</li> <li>- the block is read and verified</li> <li>- the 1 is shifted left 1 position etc.</li> </ul> <p>next:</p> <ul style="list-style-type: none"> <li>- all words of a 4k/16k block receive their address values as contents</li> <li>- these values are verified</li> <li>- tests the TMP-TPM dialogue</li> </ul>	code 5 all lamps lit

SHORT DESCRIPTION TESTPROGRAM CPUTSC SEE CHAPTER 9.5

## 10.6 SHORT ROUTINES

SEE CHAPTER 9.6

